

DR. BENEDIKT RÖSNER



- 📄 **Profound Experience in XFEL Experiments**
- 📄 **Wide Expertise in X-ray Spectroscopy**
- 📄 **Expert in Diffractive X-ray Optics**
- 📄 **Numerous International Collaborations and Research Projects**

RESEARCH ACTIVITIES

Simultaneous single shot, time-resolved demagnetization **dynamics at two energies**

Generation of **optical vortices** in the extreme ultraviolet

Creation and metrology of **X-ray transient gratings**

Spectroscopy at free electron lasers using beam splitters for **normalization of SASE modes**

New experimental schemes in **RIXS** to introduce **energy or time dispersion**

Soft X-ray microscopy with **7 nm spatial resolution for magnetic imaging**

Spin-crossover in iron(II)-complexes

<https://www.psi.ch/lmn/benedikt-roesner>

KEY SKILLS

Scientific skills:

Profound expertise in XFEL experiments

- Frequent participation in beamtimes
- **XAS, RIXS, fs dynamics, X-ray transient gratings, optical vortices, beam profiling, scattering experiments**
- Currently preparing four FEL beamtimes

Comprehensive knowledge in **X-ray microscopy and spectroscopy**

Expert in **nanolithography, nanofabrication and diffractive X-ray optics**

Successful planning and performance of several **experiments at large scale facilities as Principal Investigator**

International collaborations and research projects, existing network in the field

Successful in **publishing and proposal writing**

Computational skills:

comprehensive knowledge in state-of-the-art image and data processing software

C basic programming skills

MATLAB advanced skills and solution-based programing especially in data processing

LABVIEW basic knowledge without programing practise

PHYTON basic knowledge and programing of small scripts

LINUX use on a regular basis in our lab

Language skills:

GERMAN indigenous speaker, good comprehension of Swiss German

ENGLISH excellent knowledge of written and spoken English

POLISH advanced knowledge of written and spoken Polish

Ambitions to learn French and Italian

Miscellaneous:

CERTIFIED AMBULANCE OFFICER

SCIENTIFIC

CAREER

- 01/2016 up to now Scientist within the Laboratory for Micro- and Nanofabrication
at the Paul Scherrer Institut in Switzerland
- 10/2011 – 12/2015 PhD at the Friedrich-Alexander-Universität Erlangen-Nürnberg
MAGNA CUM LAUDE
- 03/2013 **Hercules School Grenoble**
Dedicated training on synchrotron radiation and neutron scattering

ACADEMIC

BACKGROUND

- 10/2006 – 10/2011 Chemistry studies at the Friedrich-Alexander-Universität Erlangen-Nürnberg
- 09/2011 Graduation as Master of Science with an excellent degree of 1.1
TRANSPORT PROPERTIES OF NANOSTRUCTURED THIN FILMS (rated with 1.0)
- 07/2010 – 01/2011 Exchange semester at the University of Wollongong in Australia
- 08/2009 Graduation as Bachelor of Science
SELF-ORGANIZED MICROSPHERES AS TEMPLATES FOR CONTROLLED AG-TCNQ GROWTH
(rated with 1.3)

SCIENTIFIC SOCIETIES & ACADEMIC PROGRAMS

- Deutsche Physikalische Gesellschaft (DPG)
Graduate School Molecular Science (GSMS)
Fellow in the Graduate Course (GRK 1896)
"In-Situ Microscopy with Electrons, X-rays and Scanning Probes"

1. **Diffraction X-ray Optics for Synchrotrons and Free-Electron Lasers**
C. David, B. Rösner, F. Döring, V. A. Guzenko, F. Koch, M. Lebugle, F. Marschall, G. Seniutinas, J. Raabe, B. Watts, D. Grolimund, Z. Yin, M. Beye, S. Techert, J. Viehhaus, G. Falkenberg, C. Schroer
Microscopy and Microanalysis 24 (Suppl. 2), **2018**, 264-265
<https://doi.org/10.1017/S1431927618013673>
2. **1D-Full Field Microscopy of Elastic and Inelastic Scattering with Transmission off-axis Fresnel Zone Plates**
F. Döring, F. Marschall, Z. Yin, B. Rösner, M. Beye, P. Miedema, K. Kubiček, L. Glaser, D. Raiser, J. Soltau, V. A. Guzenko, J. Viehhaus, J. Buck, M. Risch, S. Techert, C. David
Microscopy and Microanalysis 24 (Suppl. 2), **2018**, 182-183
<https://doi.org/10.1017/S1431927618013260>
3. **STXM_deconv – a MATLAB script for the Deconvolution of STXM Images**
J. L. Ornelas, B. Rösner, A. Späth, R. H. Fink
Microscopy and Microanalysis 24 (Suppl. 2), **2018**, 120-121
<https://doi.org/10.1017/S1431927618012990>
4. **7 nm Spatial Resolution in Soft X-ray Microscopy**
B. Rösner, F. Koch, F. Döring, V. A. Guzenko, M. Meyer, J. L. Ornelas, A. Späth, R. H. Fink, S. Stanescu, S. Swaraj, R. Belkhou, B. Watts, J. Raabe, C. David
Microscopy and Microanalysis 24 (Suppl. 2), **2018**, 270-271
<https://doi.org/10.1017/S1431927618013697>
5. **Extreme-Ultraviolet Vortices from a Free-Electron Laser**
P. R. Ribič, B. Rösner, D. Gauthier, E. Allaria, F. Döring, L. Foglia, L. Gianessi, N. Mahne, M. Manfreda, C. Masciovecchio, R. Mincigrucci, N. Mirian, E. Principi, E. Roussel, A. Simoncig, S. Spampinati, C. David, G. de Ninno
Microscopy and Microanalysis 24 (Suppl. 2), **2018**, 292-293
<https://doi.org/10.1017/S1431927618013806>
6. **In-operando soft X-ray microspectroscopy of organic electronic devices**
R. H. Fink, B. Rösner, X. Du, A. Späth, M. Johnson, T. Hawly, B. Watts, J. Raabe, L. Gregoratti, M. Amati
Microscopy and Microanalysis 24 (Suppl. 2), **2018**, 424-425
<https://doi.org/10.1017/S143192761801437X>
7. **Chemical changes in NEXAFS of hybrid organic-inorganic resists upon exposure**
R. Fallica, B. Watts, B. Rösner, G. della Gustina, L. Brigo, G. Brusatin, Y. Ekinic
Nanotechnology 29, **2018**, 36LT03
<https://doi.org/10.1088/1361-6528/aaccd4>
8. **Exploiting Atomic Layer Deposition for Fabricating Sub-10 nm X-ray Lenses**
B. Rösner, F. Koch, F. Döring, J. Bosgra, V. A. Guzenko, E. Kirk, M. Meyer, J. L. Ornelas, R. H. Fink, S. Stanescu, S. Swaraj, R. Belkhou, B. Watts, J. Raabe, C. David
Microelectronic Engineering 191, **2018**, 91-96
<https://doi.org/10.1016/j.mee.2018.01.033>
9. **Sub-10 nm Electron and Helium Ion Beam Lithography Using a Recently Developed Alumina Resist**
A. Cattoni, D. Mailly, O. Dalstein, M. Faustini, G. Seniutinas, B. Rösner, C. David
Microelectronic Engineering 193, **2018**, 18-22
<https://doi.org/10.1016/j.mee.2018.02.015>
10. **Nanoimprint Stamps with Ultra-High Resolution: Optimal Fabrication Techniques**
M. Graczyk, A. Cattoni, B. Rösner, G. Seniutinas, A. Kvennefors, A. Löfstrand, D. Mailly, C. David, I. Maximov
Microelectronic Engineering 190, **2018**, 73-78
<https://doi.org/10.1016/j.mee.2018.01.008>

11. **High Resolution Beam Profiling of X-ray Free Electron Laser Radiation by Polymer Imprint Development**
B. Rösner, F. Döring, P. R. Ribič, D. Gauthier, E. Principi, C. Masciovecchio, M. Zangrando, J. Vila-Comamala, G. de Ninno, C. David
Optics Express 25, **2017**, 30686-30695
<https://doi.org/10.1364/OE.25.030686>
12. **Extreme-Ultraviolet Vortices from a Free-Electron Laser**
P. R. Ribič, B. Rösner, D. Gauthier, E. Allaria, F. Döring, L. Foglia, L. Gianessi, N. Mahne, M. Manfredda, C. Masciovecchio, R. Mincigrucci, N. Mirian, E. Principi, E. Roussel, A. Simoncig, S. Spampinati, C. David, G. de Ninno
Physical Review X 7, **2017**, 031036
<https://dx.doi.org/10.1103/PhysRevX.7.031036>
13. **Transmission zone plates as analyzers for efficient parallel 2D RIXS-mapping**
F. Marschall, Z. Yin, M. Beye, J. Buck, F. Döring, V. A. Guzenko, K. Kubicek, J. Rehanek, D. Raiser, B. Rösner, A. Rothkirch, S. T. Veedu, J. Vieffhaus, C. David, S. Techert
Scientific Reports 7, **2017**, 8849
<https://dx.doi.org/10.1038/s41598-017-09052-0>
14. **Zone plates as imaging analyzers for resonant inelastic x-ray scattering**
F. Marschall, D. McNally, V. A. Guzenko, B. Rösner, M. Dantz, X. Lu, L. Nue, V. Strocov, T. Schmitt, C. David
Optics Express 25, **2017**, 15624
<https://dx.doi.org/10.1364/OE.25.015624>
15. **Interlaced zone plate optics for hard X-ray imaging in the 10 nm range**
I. Mohacsi, I. Vartiainen, B. Rösner, M. Guizar-Sicairos, V. A. Guzenko, I. McNulty, R. Winarski, M. V. Holt, C. David
Scientific Reports 7, **2017**, 43624
<https://dx.doi.org/10.1038/srep43624>
16. **In-operando studies of Ag-TCNQ nanocrystals using Raman and soft x-ray microspectroscopy**
B. Rösner, U. Schmidt, R. H. Fink
Journal of Physics: Conference Series 849, **2017**, 012016
<https://dx.doi.org/10.1088/1742-6596/849/1/012016>

2016 and before

17. **Switching behaviour of individual Ag-TCNQ nanowires: An in situ transmission electron microscopy study**
K. Ran, B. Rösner, B. Butz, R. H. Fink, E. Spiecker
Nanotechnology 27, **2016**, 425703
<https://dx.doi.org/10.1088/0957-4484/27/42/425703>
18. **Reversible Photoswitching of a Spin-Crossover Molecular Complex in the Solid State at Room Temperature**
B. Rösner, M. Milek, A. Witt, B. Gobaut, P. Torelli, R. H. Fink, M. M. Khusniyarov
Angewandte Chemie Int. Ed. 54, **2015**, 12976-12980
<https://dx.doi.org/10.1002/anie.201504192>
19. **A microspectroscopic insight into the resistivity switching of individual Ag-TCNQ nanocrystals**
B. Rösner, K. Ran, B. Butz, U. Schmidt, E. Spiecker, R. H. Fink
Physical Chemistry Chemical Physics 17, **2015**, 18278-18281
<https://dx.doi.org/10.1039/c5cp02207j>
20. **Nanomorphology in thin films of acetamide end-functionalised quaterthiophene**
N. Zeilmann, B. Rösner, A. Späth, U. Schmidt, R. H. Fink
Thin Solid Films 583, **2015**, 108-114
<https://dx.doi.org/10.1016/j.tsf.2015.03.066>
21. **Dispersion and Characterization of Arc Discharge Single-Walled Carbon Nanotubes - Towards Conducting Transparent Films**
B. Rösner, D. M. Guldi, J. Chen, A. I. Minett, R. H. Fink
Nanoscale 6, **2014**, 3695-3703
<https://dx.doi.org/10.1039/C3NR05788G>

- 22. Employing microspectroscopy to track charge trapping in operating pentacene OFETs**
B. Rösner, N. Zeilmann, U. Schmidt, R. H. Fink
Organic Electronics 15, **2014**, 435-440
<https://dx.doi.org/10.1016/j.orgel.2013.12.002>
- 23. The role of solvation effects in the growth of TCNQ-based charge-transfer salts**
B. Rösner, A. Späth, R. H. Fink
Journal of Crystal Growth 380, **2013**, 34-38
<https://dx.doi.org/10.1016/j.jcrysgro.2013.05.031>
- 24. Oxidation-driven self-assembly gives access to high-nuclearity molecular copper vanadium oxide clusters**
J. Forster, B. Rösner, R. H. Fink, L. C. Nye, I. Ivanovic-Burmazovic, K. Kastner, J. Tucher, C. Streb
Chemical Science 4, **2013**, 418-424
<https://dx.doi.org/10.1039/C2SC20942J>
- 25. Tuning the light absorption of vanadium clusters**
Johannes Forster, Benedikt Rösner, Marat M. Khusniyarov, Carsten Streb,
Chemical Communications 47, **2011**, 3114-3116
<http://dx.doi.org/10.1039/c0cc05536k>